Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,947	CHEN ET AL.	
Examiner	Art Unit	
Gonal C. Ray	2111	

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SEARCHED			
Class	Subclass	Date	Examiner
710	8,305,313- 317,105,7 1,72	10/4/2005	GCR
709	227,250	10/4/2005	GCR
709	253	10/4/2005	GCR
340	825,2.1	10/4/2005	GCR
713	300	10/4/2005	GCR
361	683,686	10/4/2005	GCR
379	242,270	10/4/2005	GCR
379	335	10/4/2005	GCR
370	257,351	10/4/2005	GCR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	9/29/2005	GCR
EAST: USPT (see search history printouts)	9/29/2005	GCR.
NPL: IEEE Xplore (see search history printouts)	9/29/2005	GCR
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